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Joint ICTP/IAEA Workshop on Advanced Simulation and Modelling for Ion Beam Analysis | (smr 2015)

Friday 27 February 2009

IBA XVII Complementary Techniques

XPS, ellipsometry, FIB, SEM, SIMS, profilometry (DEKTAK, AFM etc) - Adriatico Guest House Kastler Lecture Hall (09:45-10:30)

time	title	presenter
09:45	IBA XVII Complementary Techniques XPS, ellipsometry, FIB, SEM, SIMS, profilometry (DEKTAK, AFM etc)	